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September 1, 2006  
Signed Michelle Chan  
Michelle Chan

Appl. No. : 10/796,413 Confirmation No. 9041  
Applicant : Xiangfeng Duan et al.  
Filed : March 10, 2004  
TC/A.U. : 2891  
Examiner : Matthew Reames  
Docket No. : 01-004100  
Customer No. : 33140  
Title : Nano-enabled Memory Devices and Anisotropic Charge Carrying  
Arrays

Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

### INFORMATION DISCLOSURE STATEMENT

Sir:

The references cited on the attached form PTO/SB08A-B are being called  
to the attention of the Examiner. Pursuant to 37 CFR §1.98(a)(2), copies of all foreign  
patent documents and non US Patent and US Patent application publications are  
enclosed.

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It is respectfully requested that the cited information be expressly  
considered during the prosecution of this application, and the references be made of  
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As provided for by 37 CFR §1.97(g) and (h), no inference should be made that the information and references cited are prior art merely because they are in this statement and no representation is made that a search has been conducted or that this statement encompasses all possible relevant information.

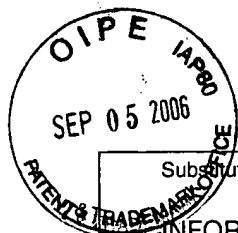
This information disclosure statement is being filed after the mailing date of the first Office Action and more than three months after the filing date, but prior to the mailing of a Notice of Allowance or Final Office Action. Authorization to charge the appropriate fee to the undersigned's deposit account is submitted herewith. Please charge any additional fees or credit any overpayment to Deposit Account No. 50-2336.

Respectfully submitted,



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Substitute for form 1449A/PTO <b>INFORMATION DISCLOSURE STATEMENT BY APPLICANT</b> <i>(use as many sheets as necessary)</i>		Complete if Known		
		Application Number	<b>10/796,413</b>	
		Filing Date	<b>March 10, 2004</b>	
		First Named Inventor	<b>Duan</b>	
		Art Unit	<b>2891</b>	
Examiner Name	<b>Matthew Reames</b>			
Sheet		of	Attorney Docket Number	<b>01-004100</b>

U.S. PATENT DOCUMENTS					
Examiner Initials	Cite No.	Document No.	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, lines, Where Relevant Passages or Relevant Figures Appeal
		Number - Kind Code (if known)			
	AA	US-5,714,766	02-03-1998	Chen et al.	
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	AC	US-6,054,349	04-25-2000	Nakajima et al.	
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	AQ	US-20040130941	07-08-2004	Kan et al.	
	AR	US-20050072989	04-07-2005	Bawendi et al.	

FOREIGN PATENT DOCUMENTS						
Examiner Initials	Cite No.	Foreign Patent Document	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	T
		Country Code - Number - Kind Code (if known)				
	AS	WO-0103208	01-11-2001	Harvard		
	AT	WO-0217362	02-28-2002	Harvard		
	AU	WO-0248701	06-20-2002	Harvard		
	AV	WO-2005017962	02-24-2005	Nanosys		

Examiner Signature		Date Considered	
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\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Substitute for form 1449A/PTO  <b>INFORMATION DISCLOSURE STATEMENT BY APPLICANT</b>  <i>(use as many sheets as necessary)</i>		<b>Complete if Known</b>		
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Examiner Name	<b>Matthew Reames</b>			
Sheet		of	Attorney Docket Number	<b>01-004100</b>

OTHER PRIOR ART - NON PATENT LITERATURE DOCUMENTS				
Examiner Initials	Cite No.	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and-or country where published.	T	
	AW	ATWATER, H.A. "Silicon nanoparticle engineering for novel logic and memory applications" Project Overview, Functional Nanostructures Program, NSF (January 2001)		
	AX	BELL, L.D. et al., "A Radiation-tolerant, low-power non-volatile memory based on silicon nanocrystal quantum dots" Innovative Approaches to Outer Planetary Exploration 2001-2020 (Publication date unknown)		
	AY	BODEFIELD, M.C. et al., "Storage of electrons and holes in self-asssembled InAs quantum dots" <i>Appl. Phys. Lett.</i> (1999) 74(13):1839-1841		
	AZ	CASPERSON, J.D. et al., "Materials issues for layered tunnel barrier structures" <i>J. Appl. Phys.</i> (2002) 92(1):261-267		
	BA	CHAE, D-H et al., "Nanocrystal memory cell using high-density SiGe Quantum Dot Array" <i>J Kor. Phys. Soc.</i> (1999) 35:S995-S998		
	BB	CORSO, D. et al., "Localized Charge storage in nanocrystal memories: feasibility of a multi-bit cell" (Publication and Publication date unknown)		
	BC	DE BLAUWE, J. "Nanoparticle Nonvolatile Memory Devices," <i>IEEE Trans. Nanotechnology</i> (2002) 1:72		
	BD	DREXLER, H. et al., "Spectroscopy of quantum levels in charge-tunable InGaAs quantum dots" <i>Phys. Ref. Lett</i> (1994) 73:2252-2255		
	BE	IANNACCONE, G. et al., "Simulation of a quantum-dot flash memory," <i>J. Appl. Phys.</i> (1998) 84(9):5032-5036		
	BF	KAN, E. "Technology for self-assembled entities in logic and memory units below the lithography limit" Cornell Nanoscale Facility (Publication date unknown)		
	BG	TAKATA, M. et al. "Fundamental characteristics of new non-volatile memory with extremely high density metal quantum dots" (Publication and Publication Date unknown)		
	BH	TIWARI, S. et al., "Volatile and Non-Volatile Memories in Silicon with Nano-Crystal Storage," <i>IEDM</i> (1995) 95-521		
	BI	TIWARI, S. et al., "A silicon nanocrystals based memory" <i>Appl. Phys. Lett</i> (1996) 68(10):1377-1379		
	BJ	VAMPOLA, K. et al., "Growth and Characterization of metal nanocrystals" Cornell Nanofabrication Facility (Publication date unknown)		
	BK			
	BL			

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